DON Normaliano	20220721002 1 DCN De			N D-1	1.1.21 2022			
PCN Number:				<u> </u>			N Date:	July 21, 2022
Title: Qualify additional Assembly sites for select SOT devices								
Customer Contact: PCN Manager Dept: Quality Services								
Proposed 1 st Ship Oct 19, 2		2022	-	e Requests a	ассе	pted	Aug 21, 2022*	
Date: until: Aug 21, 202 *Sample requests received after Aug 21, 2022 will not be supported.								
Change Type:	S IECE	iveu aite	a Aug Z	1, 202	will flot be	Supp	porteu.	
Assembly Site			□ Doci	an			Wafar Bu	mn Cita
_	000		☐ Desi	_		Wafer Bump Site		
Assembly Proc			Data Sheet		Wafer Bump Material		•	
Assembly Mate		tion.	☐ Part number change☐ Test Site		Wafer Bump Process			
Mechanical SpPacking/Shipp						H	Wafer Fab Site	
	ing/La	bening	☐ Test Process		片	☐ Wafer Fab Materials ☐ Wafer Fab Process		
				CN Da	+= :I=		Walei Fa	D Process
D			<u> </u>	CN De	talis			
Description of Ch				:		. C !	al:L:a.a1 A	
Texas Instruments								
devices listed belov sites are as follows		e product	arrected	section	. Construction	n into	ormation a	nd all assembly
sites are as rollows	•							
			SOT-23	(DBZ) Bui	ld Sites			
	Asse	mbly Sites			VA, HFTFAT, ASEV	VH, TII	EMA	
		Finish	•		Au, Matte Sn			
	Mold				SID#R-27			
		oound			D#450179			
	ļ		4222198-0028					
			SID#A-09 SID# A-03					
	Mour	-	4207123-0001					
	Com	oound	SID#400180					
	D	1 \ \ \ C	SID#1120999A2					
	Bond Wire Au, Cu							
Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part</u> <u>number</u> , for example; <u>TLV803EB33VDBZR</u> – can ship with both Matte Sn and NiPdAu. When available customers may specify NiPdAu finish by ordering the part with the G4 suffix, e.g.								
TLV803EB33VDB	ZR."							
Reason for Chang	ie:							
Continuity of Supply								
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):								
None								
Impact on Environmental Ratings								
•								
Checked boxes indi change. If below bo ratings.								
RoHS			REACH		Green Sta	itus		IEC 62474

Changes to product identification resulting from this PCN:

Assembly Site				
HNA	Assembly Site Origin (22L)	ASO: HNT		
HFTF	Assembly Site Origin (22L)	ASO: HFT		
TI Melaka (TIEM)	Assembly Site Origin (22L)	ASO: CU6		
ASEWH	Assembly Site Origin (22L)	ASO: AWH		
CDAT	Assembly Site Origin (22L)	ASO: CDA		
TFME	Assembly Site Origin (22L)	ASO: NFM		
TIPI	Assembly Site Origin (22L)	ASO: PHI		

Sample product shipping label (not actual product label)

E4/G4: NiPdAu E3/G3: Matte Sn

TEXAS
INSTRUMENTS
MADE IN: Malaysia
2DC: 20;

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

PPTH: 5A (L)TO: 1750

(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

SN1906047DBZR	TLV803EA43VDBZR	TLV809EA22DBZR	TLV810EA29DBZR
SN1906048DBZR	TLV803EB26RDBZR	TLV809EA26DBZR	TMP235A2DBZR
SN1907022DBZR	TLV803EB29DBZR	TLV809EA29DBZR	TMP235A2DBZT
SN1907023DBZR	TLV803EB33VDBZR	TLV809EA30DBZR	TMP235A4DBZR
TLV803EA22DBZR	TLV803EB42VDBZR	TLV809EA43DBZR	TMP235A4DBZT
TLV803EA26DBZR	TLV803EC29DBZR	TLV809EA45DBZR	TMP236A2DBZR
TLV803EA26RDBZR	TLV803EC30DBZR	TLV809EA46DBZR	TMP236A2DBZT
TLV803EA29DBZR	TLV803EC43DBZR	TLV809EC26DBZR	TMP236A4DBZR
TLV803EA29RDBZR	TLV803ED29DBZR	TLV809EC46DBZR	TMP236A4DBZT
TLV803EA42RDBZR	TLV803EF26DBZR	TLV809ED29DBZR	TPS61322DBZR
TLV803EA43DBZR	TLV803EF29DBZR	TLV809EF30DBZR	TPS61322DBZT
TLV803EA43RDBZR			



SOT-23 Qualification Report

Data Displayed as: Number of lots / Total sample size / Total failed

	Stress Test	Duration	PHI TPS76933DBV	CDAT TLV9061IDBV
	Temperature Cycling -65/150C	500 Cycles		
TC	Or	Or	3/231/0	3/231/0
	Temperature Cycling -55/150C	1000 Cycles		
HAST/ THB	Biased HAST 130C/85%RH Or Temperature Humidity Bias 85C/85%RH	96 hours Or 1000 hours	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C Or High Temp. Storage Bake 170C	1000 hours Or 420 hours	3/231/0	3/231/0
AC/ UHAST	Autoclave 121C Or Unbiased HAST, 130C/85%RH	96 hours	3/231/0	3/231/0
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0	3/66/0
WBP	Wire Bond Pull	Wires	3/228/0	3/228/0
WBS	Wire Bond Shear	Wires	3/228/0	3/228/0
MQ	Manufacturability	-	Pass	Pass

	Stress Test	Duration	TFME SN74AHC1G14DBV	HNA INA293A1IDBV
TC	Temperature Cycling -65/150C Or Temperature Cycling -55/150C	500 Cycles Or 1000 Cycles	3/231/0	3/231/0
HAST/ THB	Biased HAST 130C/85%RH Or Temperature Humidity Bias 85C/85%RH	96 hours Or 1000 hours	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C Or High Temp. Storage Bake 170C	1000 hours Or 420 hours	3/231/0	3/231/0
AC/ UHAST	Autoclave 121C Or Unbiased HAST, 130C/85%RH	96 hours	3/231/0	3/231/0
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0	3/66/0 (SN74LVC1GU04DBV)
WBP	Wire Bond Pull	Wires	3/228/0	3/228/0
WBS	Wire Bond Shear	Wires	3/228/0	3/228/0
MQ	Manufacturability	-	Pass	Pass

	Stress Test	Duration	TIEMA DAC121\$101CIMK	HFTAT TLV70333DBV	ASEWH TL431CDBV
TC	Temperature Cycling -65/150C Or Temperature Cycling -55/150C	500 Cycles Or 1000 Cycles	3/231/0	3/231/0	3/231/0
HAST/ THB	Biased HAST 130C/85%RH Or Temperature Humidity Bias 85C/85%RH	96 hours Or 1000 hours	3/231/0	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C Or High Temp. Storage Bake 170C	1000 hours Or 420 hours	3/231/0	3/231/0	3/231/0
AC/ UHAST	Autoclave 121C Or Unbiased HAST, 130C/85%RH	96 hours	3/231/0	3/231/0	3/231/0
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0 (LM2660MM/NOPB)	3/66/0 (TLV74333PDBV)	3/66/0
WBP	Wire Bond Pull	Wires	3/228/0	3/228/0	3/228/0
WBS	Wire Bond Shear	Wires	3/228/0	3/228/0	3/228/0
MQ	Manufacturability	-	Pass	Pass	Pass

All qualification devices in the tables are qualified at L1-260C MSL rating.

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, and HTSL, as applicable
- The following are equivalent HTSL options based on activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

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